

Title of Change:	Qualification of Die Technology Change from Open Junction Technology to Glass Passivation Technology for Fast Recovery Diode.				
Proposed first ship date:	8 June 2018 or earlier after customer approval				
Contact information:	Contact your local ON Semiconductor Sales Office or < <u>norsahida.sahman@onsemi.com</u> >				
Samples:	Contact your local ON Semiconductor Sales Office				
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or < <u>Lalan.Ortega@onsemi.com</u> >				
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <pcn.support@onsemi.com>.</pcn.support@onsemi.com>				
Change Part Identification:	There will be no change in device marking scheme. Clean date code will be advised later.				
Change category:	🔲 Wafer Fab Change 🛛 Assembly Change	Test Change Other			
Change Sub-Category(s): Manufacturing Site Chang Manufacturing Process Ch		<ul> <li>Datasheet/Product Doc change</li> <li>Shipping/Packaging/Marking</li> <li>Other:</li> </ul>			
Sites Affected:	ON Semiconductor Sites: None	External Foundry/Subcon Sites: Suzhou Good-Ark Electronics Co. Ltd.			
Description and Purpose:					
This is a Final Product Change Notification announcing to customers that ON Semiconductor is qualifying glass passivated technology on Fast Recovery Diode.					
This change is being driven by tightening environmental restrictions. This situation has forced the discontinuation of the OJR production. Life time buys of OJR product will not be possible thus the equivalent glass passivated devices will be offered.					
	Before Change Description	After Change Description			
Die	Open junction technology	Glass passivation technology			
		o change In part marking and part numbering. The GPP are not qualified to automotive standards and are not			

recommended for automotive applications.



**Reliability Data Summary:** 

QV DEVICE NAME: 1N4937RLG RMS: S42915 & S43656 PACKAGE: DO41 (DO204AL)

Test	Specification	Condition	Interval	Results
HTRB	JESD22-A108	Ta=150°C, 80% max rated V	504 hrs	0 / 80
HTSL	JESD22-A103	Ta= 150°C	1008 hrs	0 / 80
IOL	MIL-STD-750 (M1037) AEC-Q101	Ta=+25°C, delta Tj=100°C On/off = 2 min	7500 сус	0 / 80
тс	JESD22-A104	Ta= -55°C to +150°C	1000 cyc	0 / 80
AC	JESD22-A102	Ta = 121°C, RH = 100%, 15psig	96 hours	0 / 80
H3TRB	JESD22-A101	Ta = 85°C/85% RH, 80% max rated V	1008 hrs	0 / 80
RSH	JESD22- B106	Ta = 265C, 10 sec		0 / 30

## **Electrical Characteristic Summary:**

Electrical characteristics are not impacted.

## List of Affected Standard Parts:

Part Number	Qualification Vehicle
1N4933G	1N4937RLG
1N4933RLG	1N4937RLG
1N4934G	1N4937RLG
1N4934RLG	1N4937RLG
1N4935G	1N4937RLG
1N4935RLG	1N4937RLG
1N4936G	1N4937RLG
1N4936RLG	1N4937RLG
1N4937G	1N4937RLG
1N4937RLG	1N4937RLG



## **Appendix A: Changed Products**

Product	Customer Part Number	Qualification Vehicle	
1N4933G		1N4937RLG	
1N4933RLG		1N4937RLG	
1N4934G		1N4937RLG	
1N4934RLG		1N4937RLG	
1N4935G		1N4937RLG	
1N4935RLG		1N4937RLG	
1N4936G		1N4937RLG	
1N4936RLG		1N4937RLG	
1N4937G		1N4937RLG	
1N4937RLG		1N4937RLG	